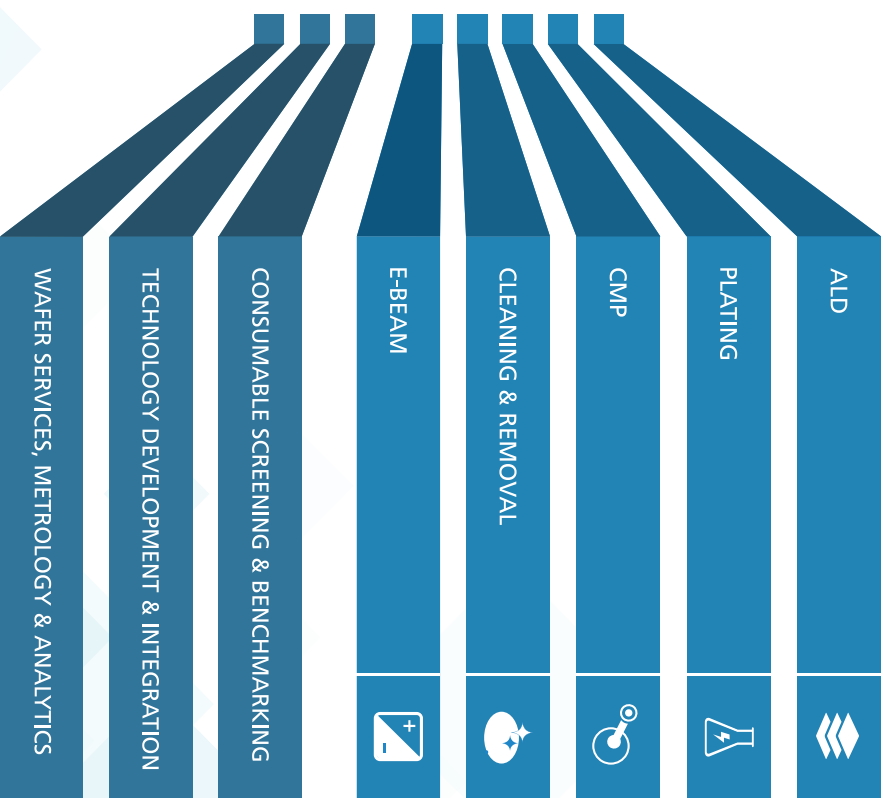
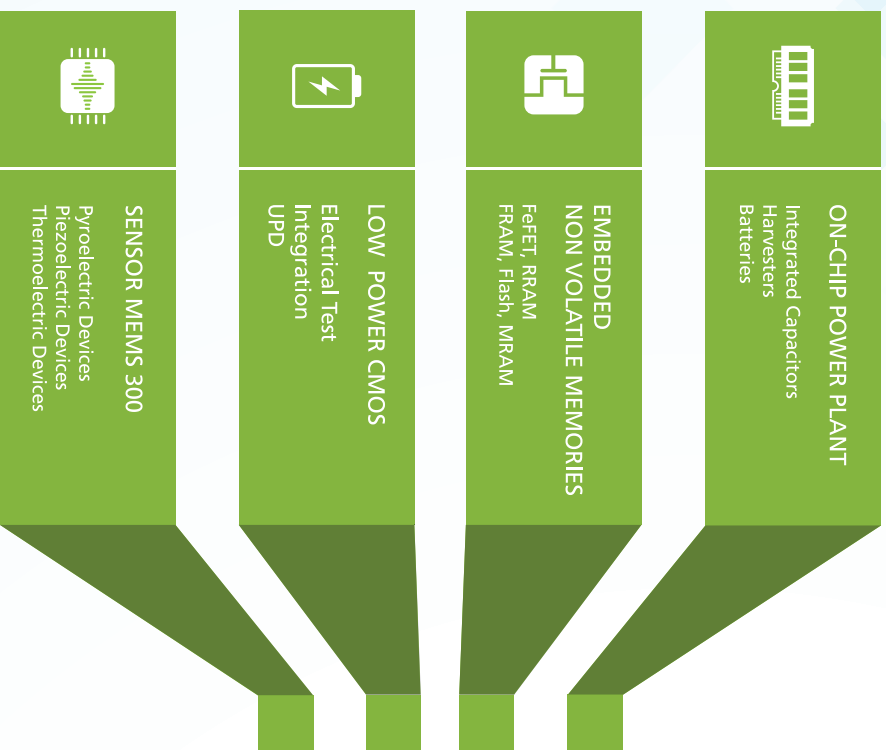


300 mm Research & Development - Dresden, Germany

DEVICES & VALUE ADDED SOLUTIONS



SCREENING FAB SERVICES

300 mm | 12 in  
200 mm | 8 in

INDUSTRY STANDARD ENVIRONMENT &  
STATE-OF-THE-ART EQUIPMENT

FAST HANDLING TIME

SEMICONDUCTOR INDUSTRY  
COLLABORATIONS

PROFESSIONAL IP  
MANAGEMENT

MORE THAN 10 YEARS  
EXPERIENCE

## EQUIPMENT LIST

### THIN FILMS / DEPOSITION

ALD / CVD Batch	A412   ASM
ALD / CVD	ALD300   FHR
ALD / CVD	Eureka 3000   Jusung
ALD / CVD	Polygon 8300 (Pulsar)   ASM
PEALD	FlexAL   Oxford Instruments
PVD / CVD	Endura   AMAT
Spin Coating	Cee Model 100 FX   Brewer Science

### NANOPATTERNING

Etch	Centura (Enabler, HART, DPS)   AMAT
Etch	Centura (Enabler, Axiom)   AMAT
Litho	SB3050DW   Vistec (50kV VSB)
Track	Cee 100x / 200x   Brewer Science
Track	Cleantrack ACT12   TEL

### ANNEAL

Anneal	Helios XP   Mattson
Cu Anneal	Formula   TEL

### WET PROCESSES

WetEtch / Clean	FC3000 WetBench   DNS
WetEtch / Clean	Semitool Raider SP   AMAT

### METALLIZATION / CMP

CMP	Reflexion LK   AMAT
CMP-support	Mobile Slurry Distribution   Stangl
ECD	Semitool Raider ECD   AMAT

### ANALYTICS

Atomprobe	LEAP 3000X Si   Imago
Ellipsometry / Porosimetry	Sopra EP5   Semilab
FIB	Strata 400   FEI
FTIR	640-IR   Agilent
Raman	InVia   Renishaw
SEM	S5000   Hitachi
TEM	Tecnai   FEI
TXRF	Picofox S2   Bruker AXS
ToF SIMS	ToFSIMS 300R   IonTof
XRD	D8 Discover   Bruker AXS

### METROLOGY / PROCESS CONTROL

AFM	X3D   Veeco
CD-SEM	Verity 4i   AMAT
Defect Detection	Aegis   NextIn
Ellipsometry	Spectra FX100   KLA
Microscope	INS3300   Vistec
Particle Measurement	SP2   KLA
Profiler	HRP340   KLA
Resistivity Measurement	RS100   KLA
Resistivity Measurement	WS-3000   Napson
Review-SEM	SEM Vision   AMAT
XPS	Theta300i   ThermoFischer
XPS	VeraFlex   ReVera
XRD / XRR	Metrix-F   Jordan Valley

### ELECTRICAL CHARACTERIZATION

Automatic Prober	Precio   TEL
Semiautomatic Prober	PA300   Süss Microtec